

To: Technology Center: 2813  
Facsimile Number: 571-273-8300

Total Pages Sent: 2

From: Jacqueline J. Garner  
Texas Instruments Incorporated  
Facsimile: 972-917-4418  
Phone: 214 532-9348

RECEIVED  
CENTRAL FAX CENTER

MAR 02 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

## In re the Application of:

	Jong Shik Yoon, et al.	Docket No.:	TI-37043
Serial No:	10/825,343	Filed:	04/15/2004
Art Unit:	2813	Examiner:	David S. Blum
Customer No.:	23494	Conf. No.:	8658
Title:	Minimizing Transistor Variations Due to Shallow Trench Isolation Stress		

## CERTIFICATION OF FACSIMILE TRANSMISSION

I hereby certify that the following papers are being transmitted by facsimile to the U.S. Patent and Trademark Office at 571-273-8300 on the date shown below:

Marianna Smith  
Marianna Smith

3-2-06  
Date

## FACSIMILE COVER SHEET

<input checked="" type="checkbox"/> FACSIMILE COVER SHEET	<input type="checkbox"/> AMENDMENT <u>X</u> (# Pages)
<input type="checkbox"/> NEW APPLICATION	<input type="checkbox"/> EOT <u>        </u> (# Page)
<input type="checkbox"/> DECLARATION (# Pages)	<input type="checkbox"/> NOTICE OF APPEAL (# Pages)
<input type="checkbox"/> ASSIGNMENT (# Pages)	<input type="checkbox"/> APPEAL <u>        </u> (# Pages)
<input type="checkbox"/> FORMAL DRAWINGS	<input type="checkbox"/> ISSUE FEE (# Pages)
<input type="checkbox"/> INFORMAL DRAWINGS	<input type="checkbox"/> REPLY BRIEF (IN TRIPLICATE) (# Pages)
<input type="checkbox"/> CONTINUATION APP'N (# Pages)	<input checked="" type="checkbox"/> Election
<input type="checkbox"/> DIVISIONAL APP'N	
NAME OF INVENTOR(S): Jong Shik Yoon, et al.	
RECEIPT DATE & SERIAL NO.: Serial No.: 10/825,343	
TITLE OF INVENTION: Minimizing Transistor Variations Due to Shallow Trench Isolation Stress	
TI FILE NO.: <b>TI-37043</b>	DEPOSIT ACCT. NO.: 20-0668
FAXED: 3/2/2006	
DUE: 3/15/2006	
ATTY/SEC'Y: JJG/ms	

This facsimile is intended only for the use of the address named and contains legally privileged and/or confidential information. If you are not the intended recipient of this telecopy, you are hereby notified that any dissemination, distribution, copying or use of this communication is strictly prohibited. Applicable privileges are not waived by virtue of the document having been transmitted by Facsimile. Any misdirected facsimiles should be returned to the sender by mail at the address indicated on this cover sheet.

Texas Instruments Incorporated  
PO Box 655474, M/S 3999  
Dallas, TX 75265

mkf  
11/10

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

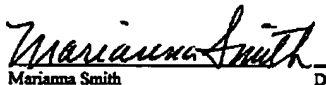
RECEIVED  
CENTRAL FAX CENTER

## In re the Application of:

	Jong Shik Yoon, et al.	Docket No.:	TI-37043	MAR 02 2006
Serial No:	10/825,343	Filed:	04/15/2004	
Art Unit:	2813	Examiner:	David S. Blum	
Customer No.:	23494	Conf. No.:	8658	
Title:	Minimizing Transistor Variations Due to Shallow Trench Isolation Stress			

ELECTION

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450


CERTIFICATION OF FAX TRANSMITTAL	
I hereby certify that the above correspondence is being facsimile transmitted to the United States Patent and Trademark Office on date shown below.	
 Mariama Smith	<u>3-2-06</u> Date

Dear Sir:

With respect to the Restriction Requirement mailed on 2/15/2006, the Examiner has restricted the instant application to the invention of Group I (Claims 1-7), or Group II (Claims 8-17), or Group III (Claims 18-20). In light of this, Applicants elect to pursue Group I, (Claims 1-7) without traverse.

The Examiner further required restriction between the species of Claim 6 and the species of Claim 7. Applicants elect the species of Claim 6, Claims 1-5 being generic.

Respectfully submitted,

  
Jacqueline J. Garner  
Attorney for Applicants  
Reg. No. 36,144

Texas Instruments Incorporated  
P.O. Box 655474, MS 3999  
Dallas, TX 75265  
(214) 532-9348